



FOR IMMEDIATE RELEASE

Aehr Test Systems

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Aehr Test Systems Added to Russell Microcap Index

Fremont, CA (June 26, 2017) – Aehr Test Systems (NASDAQ: AEHR), a worldwide supplier of semiconductor test and burn-in equipment, today announced it has been added to the Russell Microcap index, effective at the close of market on June 23, 2017 when Russell Investments reconstituted its comprehensive set of U.S. and global equity indexes.

Gayn Erickson, President and CEO of Aehr Test Systems, commented, “Aehr Test’s inclusion in the Russell Microcap index reflects our continued success in providing reliability and massively parallel test solutions to manufacturers of integrated circuits and highly-integrated miniature modules. Our advanced test and burn-in systems are helping companies that supply devices into the automotive sensor, mobile communications, IC, and Internet of Things markets meet the higher quality and reliability needs of these markets. Our systems enable the test and burn-in of packaged parts, modules, wafers and even systems, supporting the rapidly changing advanced packaging used by our customers. With the roll out of our new FOX-XP platform for wafer level test and burn-in, we believe we have built a solid foundation for growth as these dynamic end markets expand. As we execute on our strategic plan, we look forward to the additional visibility and investment community exposure that comes with being part of the Russell Microcap Index.”

The rebalanced Russell Global, Russell 1000, Russell 2000, Russell 3000, Russell Midcap, and Russell Microcap Indexes will begin trading today, June 26, 2017.

Annual Russell indexes reconstitution captures the 4,000 largest U.S. stocks as of the end of May, ranking them by total market capitalization. Membership in the Russell 3000®, which remains in place for one year, means automatic inclusion in the large-cap Russell 1000® Index or small-cap Russell 2000® Index as well as the appropriate growth and value style indexes. FTSE Russell determines membership for these indexes primarily by objective, market-capitalization rankings, and style attributes.

Russell indexes are widely used by investment managers and institutional investors for index funds and as benchmarks for active investment strategies. Approximately \$6 trillion in assets are benchmarked to the Russell U.S. indexes. Russell indexes are part of FTSE Russell, a leading global index provider.

For more information on the Russell 3000® Index and the Russell US Indexes reconstitution, go to the “Russell Reconstitution” section on the [FTSE Russell website](#).

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a worldwide provider of test systems for burning-in and testing logic and memory integrated circuits and has an installed base of more than 2,500 systems worldwide. Increased quality and reliability needs of the Automotive and Mobility integrated

circuit markets are driving additional test requirements, capacity needs and opportunities for Aehr Test products in package and wafer level test. Aehr Test has developed and introduced several innovative products, including the ABTS™ and FOX™ families of test and burn-in systems, WaferPak™ contactors, and DiePak® carriers. The ABTS systems are used in production and qualification testing of packaged parts for both low-power and high-power logic as well as memory devices. The FOX family of systems includes single and multi-wafer full wafer contact test and burn-in systems used for burn-in and functional test of complex devices, such as leading-edge memories, digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The WaferPak contactor contains a unique full wafer probe card capable of testing wafers up to 300mm that enables IC manufacturers to perform test and burn-in of full wafers on Aehr Test FOX systems. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of both bare die and modules. For more information, please visit Aehr Test's website at www.aehr.com.

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